



Micro Modular System

beyond AUTOMATION

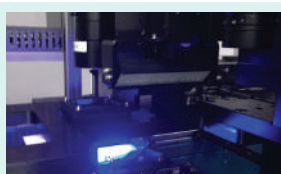
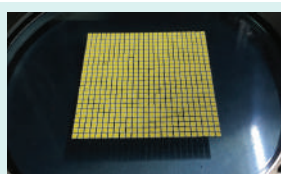
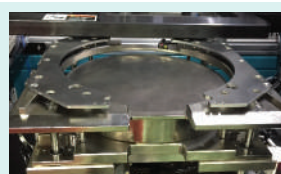
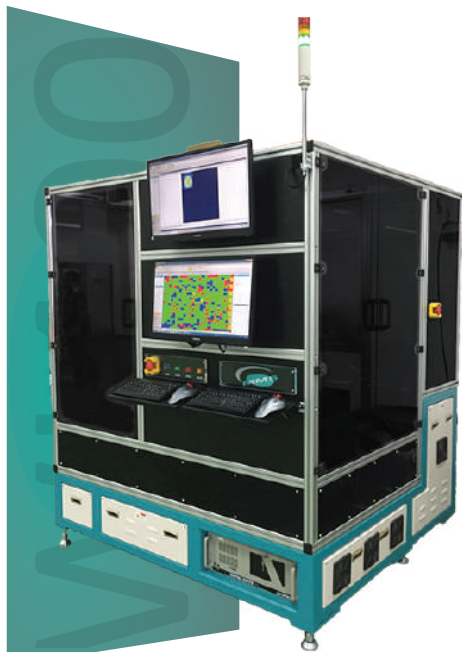
WI400

Semi Auto Wafer Inspection

WI 400 Semi Auto Wafer Inspection is designed to deliver the utmost flexibility to support top vision inspection for fabricated components on wafer such as lens, LED & IC packages from 4" tiles to 8" wafer.

With unique blend of flexibility and high performance, it makes an ideal inspection solution for automation industry.

- ▶ [Introduction](#)
- ▶ [Machine Features](#)
- ▶ [Inspection Criteria](#)
- ▶ [Machine Specification](#)
- ▶ [Applicable Products](#)



Machine Features



- **High Resoluton Camera**
Selection from 5MP to 65MP mono/color camera imaging technology
- **Integrated Techniques**
Color inspection, normalized correlation and rule based algorithms
- **Auto Alignment Function**
2D decoding & Position Recognize (PR) vision
- **Real Time Wafer Map Display**
All inspection information such as mapping map, defect region inspection results is visualized for easy reading
- **Support Common Wafer Map Output Format**
STIF files
- **Minimum Defect Size**
5 μm x 5 μm
- **Confocal Displacement Sensor**
For warpage detection. Height compensation up to 2mm

Inspection Criteria



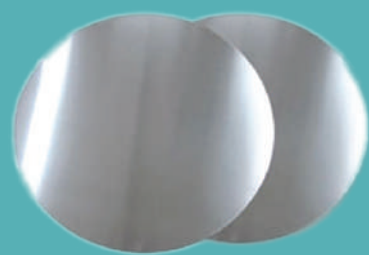
Type	
Foreign Material	Chipping
Stains	Cracked
Blistering	Damaged Bump
Scratches	Un-Separation
Lifted Metal	Off Set-Cut
Measuring	Discolor

Machine Specification

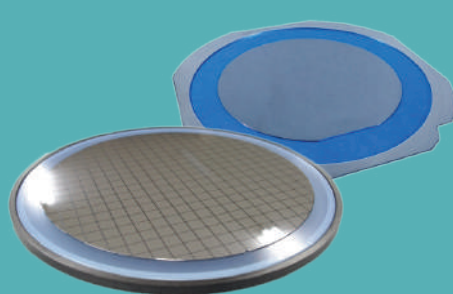


Products	6" bare wafer or 8" wafer ring	
Specifications	Input:	6" bare wafer or 8" wafer ring
	Output:	6" bare wafer or 8" wafer ring
UPH	10 K	
Vision Inspection	Cosmetic	
Footprint	1250mm(W) x 1600mm(L) x 2100mm(H)	
Warranty	1 year limited excluding wear and tear parts	

Applicable Products



Bare Wafer



Wafer Ring

Other Products



SLD 001

Laser Diode
Tester



AT 100

COB LED
Test Machine



EOL Tester

Automotive
EOL Machine



RT 800

Reliability
Test System